

CLAIMS

What is claimed is:

1. A testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing an enhanced reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires enhanced reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the enhanced reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their enhanced reliability testing flag indicates they are in need of the enhanced reliability testing; and
performing the enhanced reliability testing for the integrated circuit devices requiring the enhanced reliability testing.
2. A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing an reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing further reliability testing for the integrated circuit devices requiring the further reliability testing.

3. A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing further reliability testing for the integrated circuit devices requiring the further reliability testing.